

NOV. 25. 2003 2:14PM

NO. 898 P. 1/12

BEYER WEAVER & THOMAS, LLP

INTELLECTUAL PROPERTY LAW
2030 Addison Street, Seventh Floor, Berkeley, CA 94704
Telephone: (510) 843-6200 Facsimile: (510) 843-6203
www.beyerlaw.com

FACSIMILE COVER SHEET

November 25, 2003

RECEIVED
CENTRAL FAX CENTER

NOV 26 2003

OFFICIAL

PLEASE DELIVER TO EXAMINER IMMEDIATELY

Receiver: Examiner Kalimah Fernandez
USPTO

TEL #: 703-305-6310

FAX #: 703-746-4847

Sender: Leslie Russell, Patent Secretary for:
Phillip P. Lee

Re: U.S. Patent Application: *Film Thickness Measurement Using
Electron-Beam Induced X-Ray Microanalysis*
Inventor(s): Shing M. Lee
Application No.: 09/695,726
File Date: October 23, 2000
Our File No.: KLA1P012

Pages Including Cover Sheet(s): 12

MESSAGE:

Dear Examiner Fernandez:

Attached is a copy of the Amendment E which we mailed to the USPTO on October 2, 2003 (which was before the 3-month deadline). Also attached is a copy of the Postcard stamped received.

Thank you very much for telephone interview conducted today.

Please let us know if you require anything further.

Phillip P. Lee
Registration No. 46,866


CONFIDENTIALITY NOTE

The information contained in this facsimile (FAX) message is legally privileged and confidential information intended only for the use of the receiver or firm named above. If the reader of this message is not the intended receiver, you are hereby notified that any dissemination, distribution or copying of this FAX is strictly prohibited. If you have received this FAX in error, please immediately notify the sender at the telephone number provided above and return the original message to the sender at the address above via the United States Postal Service. Thank you.

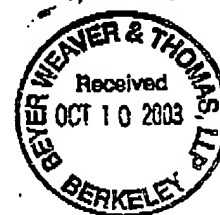
Docket #	KLA1P012/P647US	By:	PPL/lr	Date of this mailing:	October 2, 2003
App'n #:	09/695,726	Filing Date:	10/23/00		
Inv(s)	Shing M. Lee				
Title:	FILM THICKNESS MEASUREMENT USING ELECTRON-BEAM INDUCED X-RAY MICROANALYSIS				

The following have been received in the U.S. Patent Office on the date stamped hereon:

Item	Description	# Pgs
1.	Amendment Transmittal	1
2.	Amendment E	9
3.	First Class Certificate of Mailing	
4.		
5.		
6.		
7.		
8.		
9.		
10.		



BEYER WEAVER & THOMAS, LLP
 SEEN/CONFIRMED
 BY DOCKETING DEPT.
 DATE: 10/21/03 BY: *[Signature]*



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

Group: 2881

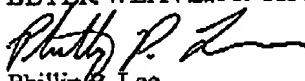
Title: FILM THICKNESS MEASUREMENT
USING ELECTRON-BEAM INDUCED
X-RAY MICROANALYSIS**CERTIFICATE OF MAILING**I hereby certify that this correspondence is being deposited with
the United States Postal Service as First Class Mail to:
Commissioner for Patents, P.O. Box 1450, Alexandria, VA
22313-1450 on October 2, 2003.Signed: 
Leslie Russell**AMENDMENT TRANSMITTAL**Mail Stop Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.
The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	22	MINUS	30	00	x 9 =	x 18 = 0.00
Independent Claims	03	MINUS	06	00	x 42 =	x 84 = 0.00
Multiple Dependent Claim Present and Fee Not Previously Paid					\$140.00	\$280.00
Total					\$	\$0.00

- ☒ Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.
- ☒ Please charge the required fees, or any additional fees required to facilitate filing the enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP
Phillip P. Lee
Reg. No. 46,866P.O. Box 778
Berkeley, CA 94704-0778